

S/N: 10/622,247  
Docket : CS01-150  
Reply to the Office action dated April 21, 2005

Page 3

**AMENDMENTS TO THE SPECIFICATION**

Please replace the paragraph beginning at Page 9 , Line 3 with the following rewritten paragraph (showing changes):

-- The features and advantages of a semiconductor device test method according to example embodiments the present invention and further details of a process of fabricating control method such a semiconductor device in accordance with embodiments of the present invention will be more clearly understood from the following description taken in conjunction with the accompanying drawings in which like reference numerals designate similar or corresponding elements, regions and portions and in which: --